

# AOT66518L

# 150V N-Channel AlphaSGT<sup>™</sup>

## **General Description**

- Trench Power MOSFET technology
- $\bullet$  Combined of low  $R_{\text{DS(ON)}}$  and wide safe operatiing area (SOA)
- Higher in-rush current enabled for faster start-up and shorter down time
- RoHS and Halogen-Free Compliant

## **Applications**

- Telecom
- Industrial Power Supply
- · Load switch

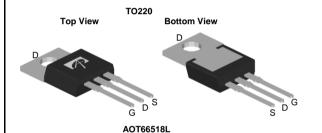
## **Product Summary**

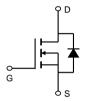
 $\begin{array}{lll} V_{DS} & 150V \\ I_{D} \; (at \; V_{GS} \! = \! 10V) & 120A \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 10V) & < 5m\Omega \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 8V) & < 5.6m\Omega \end{array}$ 

100% UIS Tested 100% Rg Tested

Max Tj=175°C







Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOT66518L	TO-220	Tube	1000

Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		$V_{DS}$	150	V	
Gate-Source Voltage		$V_{GS}$	±20	V	
Continuous Drain	T <sub>C</sub> =25°C	I_	120		
Current G	T <sub>C</sub> =100°C	I <sub>D</sub>	120	A	
Pulsed Drain Current <sup>c</sup>		I <sub>DM</sub>	480		
Continuous Drain	T <sub>A</sub> =25°C	1	30	A	
Current	T <sub>A</sub> =70°C	IDSM	25	^	
Avalanche Current <sup>C</sup>		I <sub>AS</sub>	70	А	
Avalanche energy	valanche energy L=0.3mH <sup>C</sup>		735	mJ	
Diode reverse recov $V_{DS}$ =0 to 75V, $I_F$ $\lesssim$ 30	•	di/dt	500	A/us	
	T <sub>C</sub> =25°C	P <sub>D</sub>	375	W	
Power Dissipation <sup>B</sup>	T <sub>C</sub> =100°C	' D	185	VV	
	T <sub>A</sub> =25°C	D	10	w	
Power Dissipation A	T <sub>A</sub> =70°C	P <sub>DSM</sub>	7	VV	
Junction and Storag	je Temperature Range	$T_J$ , $T_{STG}$	-55 to 175	°C	

Thermal Characteristics						
Parameter		Symbol	Тур	Max	Units	
Maximum Junction-to-Ambient A	t ≤ 10s	D	12	15	°C/W	
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	50	60	°C/W	
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	0.26	0.40	°C/W	



### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC I	PARAMETERS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		150			V
I <sub>DSS</sub> Zero Gate V	Zoro Coto Voltago Proin Current	$V_{DS}$ =150V, $V_{GS}$ =0V				1	μA
	Zero Gate Voltage Drain Current		T <sub>J</sub> =55°C			5	
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$		2.7	3.2	3.7	V
		$V_{GS}$ =10V, $I_{D}$ =20A			4.2	5	mΩ
$R_{DS(ON)}$	Static Drain-Source On-Resistance		T <sub>J</sub> =125°C		7.7	9.4	
		$V_{GS}$ =8V, $I_D$ =20A			4.6	5.6	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS}=5V$ , $I_{D}=20A$			50		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			0.68	1	V
Is	Maximum Body-Diode Continuous Curr	rent <sup>G</sup>			120	Α	
DYNAMI	CPARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =75V, f=1MHz			6460		pF
Coss	Output Capacitance				820		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				5		pF
$R_g$	Gate resistance	f=1MHz		1.1	2.3	3.5	Ω
SWITCH	NG PARAMETERS						
<b>Q</b> <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =75V, I <sub>D</sub> =20A			80	115	nC
$Q_{gs}$	Gate Source Charge				32		nC
$Q_{gd}$	Gate Drain Charge				15		nC
Q <sub>oss</sub>	Output Charge	$V_{GS}$ =0V, $V_{DS}$ =75V			273		nC
t <sub>D(on)</sub>	Turn-On DelayTime				27		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =75V, $R_L$ =2.5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			20		ns
$t_{D(off)}$	Turn-Off DelayTime				49		ns
t <sub>f</sub>	Turn-Off Fall Time				28		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt=500A/μs			86		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F$ =20A, di/dt=500A/ $\mu$	S		920		nC

A. The value of  $R_{\text{BJA}}$  is measured in a still air environment with  $T_A = 25^{\circ}$  C. The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{BJA}} \leq 10^{\circ}$  and the maximum allowed junction temperature of 175° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

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B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(MAX)}\!\!=\!\!175^\circ\,$  C.

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

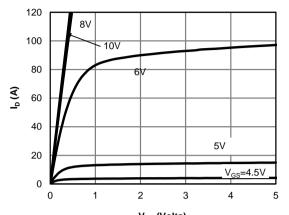
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=175° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

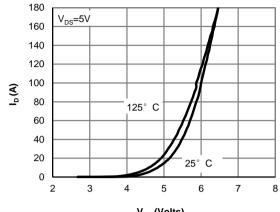
H. These tests are performed in a still air environment with  $T_A$ =25° C.



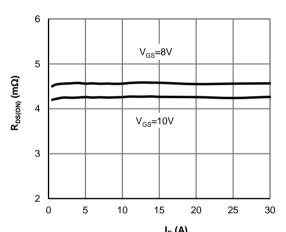
### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



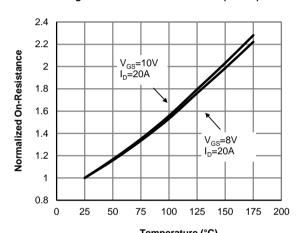
 $V_{\rm DS}$  (Volts) Figure 1: On-Region Characteristics (Note E)



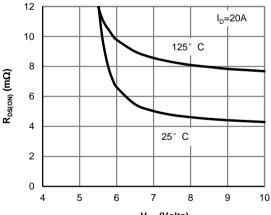
V<sub>GS</sub> (Volts) Figure 2: Transfer Characteristics (Note E)



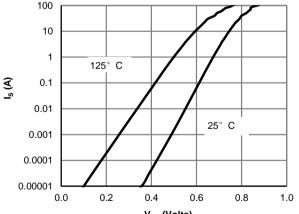
 ${\rm I_D}\left( {\rm A} \right)$  Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)



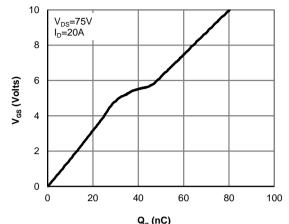
V<sub>GS</sub> (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

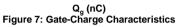


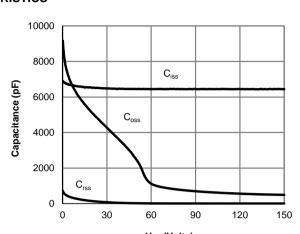
V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)



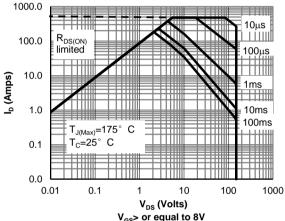
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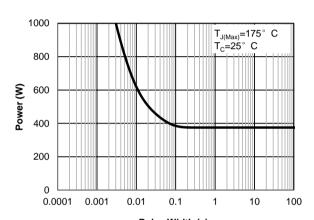




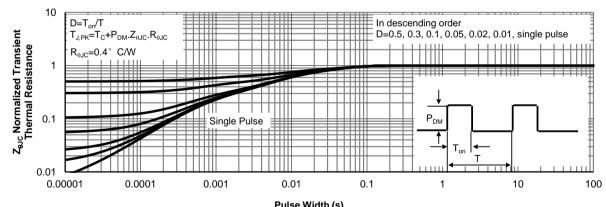
V<sub>DS</sub> (Volts)
Figure 8: Capacitance Characteristics



V<sub>GS</sub>> or equal to 8V Figure 9: Maximum Forward Biased Safe Operating Area (Note F)



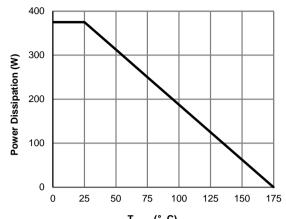
Pulse Width (s)
Figure 10: Single Pulse Power Rating Junction-toCase (Note



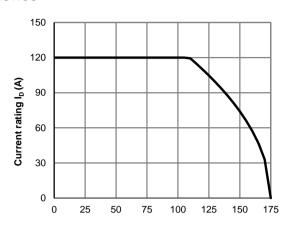
Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



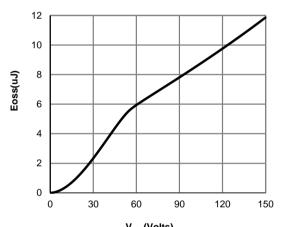
### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



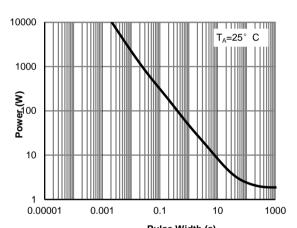
T<sub>CASE</sub> (° C) Figure 12: Power De-rating (Note F)



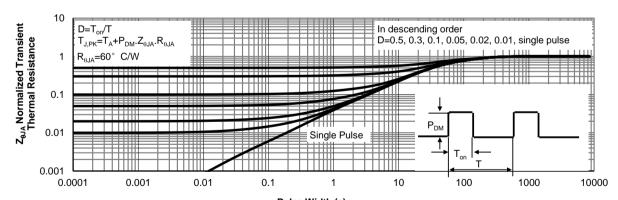
T<sub>CASE</sub> (° C)
Figure 13: Current De-rating (Note F)



V<sub>DS</sub> (Volts) Figure 14: Coss stored Energy



Pulse Width (s)
Figure 15: Single Pulse Power Rating Junctionto-Ambient (Note H)



Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

Figure A: Gate Charge Test Circuit & Waveforms

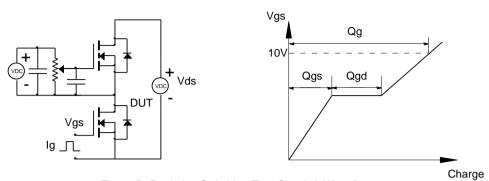


Figure B: Resistive Switching Test Circuit & Waveforms

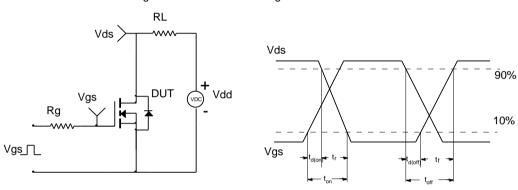


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

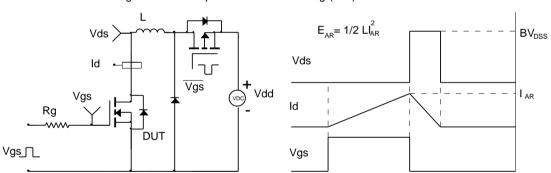
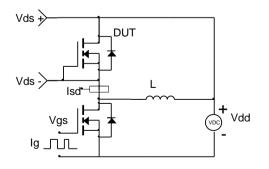
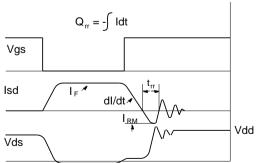


Figure D: Diode Recovery Test Circuit & Waveforms





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